IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Masayuki FURUHASHI et al.

Serial Number: Not Yet Assigned

Filed: October 29, 2003

Customer No.: 38834

For: SEMICONDUCTOR DEVICE FABRICATION METHOD AND SEMICONDUCTOR FABRICATION CONTROL METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

October 29, 2003

Sir:

In compliance with 37 CFR 1.56, Applicants call to the attention of the Patent and Trademark Office the references listed on the attached PTO-1449.

A copy of each of the references is enclosed herewith.

In the event there are any fees due in connection with the filing of this paper, please charge Deposit Account No. <u>50-2866</u>.

Respectfully submitted, WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP

Atty. Docket No.: 032077

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Enclosures: PTO-1449; References (6)

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INFORMATION DISCLOSURE								
			Atty. Do	cket No. 03	2077	Serial No. New Appln.		
STATEMENT		Applicant(s): Masayuki FURUHASHI et al.						
PTO-1449			Filing Date: October 29, 2003			Group Art Unit:		
U.S. PATENT DOCUMENTS								
Examiner Docum			ment	Name	Date		G. 1 1	E''. D
Initial		No.		Name	Date	Class	Subclass	Filing Date (If appropriate)
	AA							
<u>-</u>	AB							
<u></u>	AC							
	AD							
FOREIGN PATENT DOCUMENTS								
	·•	Doc No.	ument	Date	Country	Translat (Yes or		
	AE	9-32	26396	12/16/97	Japan	Abstract.		
	AF	2000	0-340644	12/08/00	Japan	Abstract		
	AG	10-3	313012	11/24/98	Japan	Abstract		
	АН	2001	1-102321	04/13/01	Japan	Abstract		
	AI	2001	1-102386	04/13/01	Japan	Abstract		
AJ 200		1-274154	10/05/01	Japan	Abstract			
	AK	<u> </u>						
OTHER DOCUMENTS								
	AL							
	AM							
Examiner Date Considered								